

L Number	Hits	Search Text	DB	Time stamp
1	2896924	power smae shut\$3 same off and wafer same (edge or flat) same (align or alignment or adjust or adjustment or orientation or position) same (angle or angular)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:09
2	52	power same shut\$3 same off and wafer same (edge or flat) same (align or alignment or adjust or adjustment or orientation or position) same (angle or angular)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:09
4	882	wafer same (flat or edge) same shift	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:20
3	1	wafer adj (flat or edge) adj shift	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:13
5	1962	((702/150) or (414/935,936)).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:14
7	19	(wafer same (flat or edge) same shift) and (((702/150) or (414/935,936)).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:20
8	5	("3174392" "4457664" "4833790" "5085558" "5308222").PN.	USPAT	2004/09/29 13:18
9	3	(wafer same (flat or edge) same shift) and (((702/150) or (414/935,936)).CCLS.) and power	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:20
10	3	(wafer same (flat or edge) same shift) and (((702/150) or (414/935,936)).CCLS.) and power	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:20
11	0	wafer same (flat or edge) same shift same (angle or position or orientation or angular or rotate or rotation) and power same shut\$3 same off	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:25

12	0	wafer same (flat or edge) same (measur\$5 or sens\$3 or detect\$3 or analy\$4 or test\$3 or identif\$5 or determin\$3 or monitor\$3 or inspect\$3 or diagnos\$3) same angular same displacement and power same shut\$3 same off	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:23
13	29	wafer same (flat or edge) same (measur\$5 or sens\$3 or detect\$3 or analy\$4 or test\$3 or identif\$5 or determin\$3 or monitor\$3 or inspect\$3 or diagnos\$3) same angular same displacement	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:25
14	527	wafer same power same (shut\$3 or turn) same off	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:25
15	132	wafer same power same (shut\$3 or turn) same off same (angle or angular or position or orientation)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:27
16	3	wafer same power same (shut\$3 or turn) same off same (angle or angular or position or orientation) and relay and solenoid	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:26
17	78	wafer same power same (shut\$3 or turn) same off same (angle or angular or position or orientation) and wafer same (edge or flat)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:32
18	81	wafer same power same (shut\$3 or turn) same (off or down) same (angle or angular or position or orientation) and wafer same (edge or flat)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:30
19	3	(wafer same power same (shut\$3 or turn) same (off or down) same (angle or angular or position or orientation) and wafer same (edge or flat)) not (wafer same power same (shut\$3 or turn) same off same (angle or angular or position or orientation) and wafer same (edge or flat))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:30
20	406	power same (shut\$3 or turn) same (down or off) and wafer same (edge or flat) and (measur\$5 or sens\$3 or detect\$3 or analy\$4 or test\$3 or identif\$5 or determin\$3 or monitor\$3 or inspect\$3 or diagnos\$3) same (orientation or angle or angular)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:34

21	45	power same (shut\$3 or turn) same (down or off) and wafer same (edge or flat) same (measur\$5 or sens\$3 or detect\$3 or analy\$4 or test\$3 or identif\$5 or determin\$3 or monitor\$3 or inspect\$3 or diagnos\$3) same (orientation or angle or angular)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:34
22	7	(US-4880348-\$ or US-4449885-\$ or US-4498833-\$ or US-4836733-\$ or US-6160338-\$ or US-5452521-\$ or US-5483138-\$).did.	USPAT	2004/09/29 13:41
23	4	((US-4880348-\$ or US-4449885-\$ or US-4498833-\$ or US-4836733-\$ or US-6160338-\$ or US-5452521-\$ or US-5483138-\$).did.) and power	USPAT	2004/09/29 13:41
24	21	wafer and (edge or flat) and relay and solenoid and door and (orientation of angle or angular)	USPAT	2004/09/29 14:26
25	75	wafer same (position or orientation) same (angle or angular) and power same (shut\$3) same (off or down)	USPAT	2004/09/29 13:51
26	48	("4405435" "4498416" "4592306" "4607593" "4664062" "4681773" "4709655" "4715921" "4717461" "4722298" "4733631" "4739787" "4820106" "4825808" "4852516" "4857160" "4886592" "4917556" "4951601" "5000113" "5067218" "5076205" "5083364" "5088444" "5186718" "5199483" "5259881" "5292393" "5352248" "5380682" "5516732" "5520002" "5582866" "5611655" "5620578" "5740034" "5758680" "5769952" "5784238" "5785796" "5855681" "5873942" "5900105" "5930456" "5944857" "6017395" "6083321" "6120606").PN.	USPAT	2004/09/29 13:59
27	2	("6312525").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 14:05
28	585	(measur\$5 or sens\$3 or detect\$3 or analy\$4 or test\$3 or identif\$5 or determin\$3 or monitor\$3 or inspect\$3 or diagnos\$3) same wafer same (edge or flat) same (offset or shift).	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 14:05

29	130	(measur\$5 or sens\$3 or detect\$3 or analy\$4 or test\$3 or identif\$5 or determin\$3 or monitor\$3 or inspect\$3 or diagnos\$3) same wafer same (edge or flat) same (offset or shift) and (power or shut\$3 or turn) same (off or down)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 14:06
30	83	(measur\$5 or sens\$3 or detect\$3 or analy\$4 or test\$3 or identif\$5 or determin\$3 or monitor\$3 or inspect\$3 or diagnos\$3) same wafer same (edge or flat) same (offset or shift) and (power or shut\$3 or turn) near4 (off or down)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 14:07
31	105	(measur\$5 or sens\$3 or detect\$3 or analy\$4 or test\$3 or identif\$5 or determin\$3 or monitor\$3 or inspect\$3 or diagnos\$3) same wafer same (edge or flat) same (offset or shift) and (power or shut\$3 or turn\$3) near4 (off or down)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 14:15
32	2	("5,563,798").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 14:15
38	1560	wafer same (edge or flat or orientation or position) and door	USPAT	2004/09/29 14:27
39	836	wafer same (edge or flat or orientation or position) and door and power	USPAT	2004/09/29 14:27
37	4	wafer same (edge or flat or orientation or position) and relay same solenoid same door	USPAT	2004/09/29 14:27
-	708	(702/150).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:59
-	131	wafer same flat same shift and (angle or angular)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:36
-	266	wafer same flat same shift	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:36
-	105	(measur\$5 or sens\$3 or detect\$3 or analy\$4 or test\$3 or identif\$5 or determin\$3 or monitor\$3 or inspect\$3 or diagnos\$3) same wafer same flat same shift	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:36

	5	wafer same flat same shift and solenoid	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:38
	0	wafer adj flat adj shift	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:13
	2667	wafer adj flat	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:46
	425	wafer adj flat same (orientation or position)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:39
	5	wafer adj flat same (orientation or position) and relay and solenoid	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:39
	5	wafer adj flat same (orientation or position) and relay and solenoid and (angle or angular)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:42
	69	wafer adj flat same (orientation or position) same (angle or angular)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:44
	0	jean-hua-yuen.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:44
	0	yuen-jean-hua.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:45
	0	po-ming-chen.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:44

-	2	chen-po-ming.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:45
-	0	chiang-ming-ji.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:45
-	0	chiang-ming-j.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:45
-	0	yuen-jean.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:45
-	9	chiang-ming.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:45
-	0	yang-ji-shen.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:46
-	0	yang-ji-s\$.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:46
-	8	yang-ji.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:46
-	0	wafer adj flat and (shut\$3 adj (off or power or down)) and sensor and (angle or angular) and relay and solenoid	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:47
-	76	wafer adj flat and (shut\$3 adj (off or power or down)) and sensor and (angle or angular)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:53

	7	wafer adj flat adj alignment	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:54
	1962	((702/150) or (414/935,936)).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:14
	0	((702/150) or (414/935,936)).CCLS.) and relay and solenoid	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 17:59
	16	((702/150) or (414/935,936)).CCLS.) and wafer and flat and (angle of angular) and (position or orientation) and (power same off)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:00
	15	((702/150) or (414/935,936)).CCLS.) and wafer and flat and (angle or angular) and (position or orientation) and (power same off)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:10
	1	((702/150) or (414/935,936)).CCLS.) and wafer and flat and (angle or angular) same displacement and (position or orientation) and (power same off)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:10
	26	((702/150) or (414/935,936)).CCLS.) and wafer and flat and (angle or angular) same displacement	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:10
	6	((702/150) or (414/935,936)).CCLS.) and wafer same flat same (angle or angular) same displacement	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:10
	1	((702/150) or (414/935,936)).CCLS.) and wafer and flat and (angle or angular) same displacement and (power same off)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/28 18:11
	2	4498833.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/29 13:07
	21	4498833.URPN.	USPAT	2004/09/28 18:21